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Sheet	1	of	2	Attorney Docket Number	LVPAT026US	36	5

				U.S. PATENT DOCU	MENTS	-
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Examiner Signature Joseph D Mushay Date Considered 4/14/04	Joseph D Mushey Date Considered 4/14/04
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<sup>1</sup> Unique citation designation number. 2 See attached Kinds of U.S. Patent Documents. 3 Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). 4 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 5 Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

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	OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS	•
Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Τ2
	STEVEN F. OAKLAND, "Considerations for Implementing IEEE 1149.1 On System-on-a-Chip Integrated Circuits", International Test Conference 2000 Proceedings, October 3-5, 2000, p. 628-637	
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		item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.  STEVEN F. OAKLAND, "Considerations for Implementing IEEE 1149.1 On System-on-a-Chip Integrated Circuits", International Test Conference 2000 Proceedings, October 3-5, 2000, p. 628-637  LEE WHETSEL, "An IEEE Based Test Access Architecture for ICs With Embedded

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Sheet of 2 1

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Application Number	09/843,307							
Filing Date	04/27/2001							
First Named Inventor	NADEAU-DOSTIE							
Group Art Unit	2816							
Examiner Name	N/A							
Attorney Docket Number	LVPAT026US							

	U.S. PATENT DOCUMENTS										
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Sheet 2 of 2

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Application Number	09/843,307				
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